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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/775,103	KAWAHARA ET AL.	
Examiner	Art Unit	
Ari M. Diacou	3663	

	SEARCHED		
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
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SEARCH I (INCLUDING SEAR	NOTES CH STRATEG`	<b>(</b> )
	DATE	EXMR
Talked to Deandra Hughes	4/26/2006	AMD
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